

## Qualification Results Summary for Addition of a Polyimide Layer to the ADuM3190 Device

QUALIFICATION RESULTS / STATUS			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
High Temperature Operating Life (HTOL)*	JEDEC <i>JESD22-A108</i>	<b>7x77</b> <b>2x45</b>	<b>Pass</b>
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	<b>9x77</b>	<b>Pass</b>
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	<b>9x77</b>	<b>Pass</b>
Autoclave (AC)*	JEDEC <i>JESD22-A102</i>	<b>6x77</b> <b>3x45</b>	<b>Pass</b>
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	<b>4x77</b> <b>1x45</b>	<b>Pass</b>
Solder Heat Resistance (SHR)*	JEDEC/IPC <i>J-STD-020</i>	<b>3x10</b>	<b>Pass</b>
Latch-Up	JEDEC <i>JESD78</i>	<b>1x9</b>	<b>Pass</b> ±200mA @ +30V
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JS-001</i>	<b>1x18</b>	<b>Pass</b> ±4000V
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	<b>1x18</b>	<b>Pass</b> ±1250V

\*Preconditioned per JEDEC/IPC J-STD-020